

INTERNATIONAL STANDARD

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Guidelines for the measurement method of power durability for surface acoustic wave (SAW) and bulk acoustic wave (BAW) devices in radio frequency (RF) applications

Lignes directrices relatives à la méthode de mesure de la durabilité de puissance des appareils à ondes acoustiques de surface (OAS) et des appareils à ondes acoustiques de volume (OAV), dans les applications de radiofréquence (RF)



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CONTENTS

FOREWORD.....	3
INTRODUCTION.....	5
1 Scope.....	6
2 Normative references	6
3 Terms and definitions	6
3.1 General terms	6
3.2 Durability related terms	11
4 Basic properties of life time of RF SAW/BAW devices.....	12
4.1 Life time and accelerated testing.....	12
4.2 Failure mechanisms	14
4.2.1 General	14
4.2.2 Acoustomigration	15
4.2.3 Self-heating and thermal run-away	16
4.2.4 Other mechanisms.....	16
4.3 Modelling	16
5 Life time measurement	18
5.1 Measurement setup	18
5.2 Measurement procedure	19
5.3 Life time estimation.....	20
5.4 Measurement specifications	20
Bibliography.....	21
Figure 1 – FBAR configuration	8
Figure 2 – SMR configuration.....	9
Figure 3 – Frequency response of an n th SAW/BAW filter	9
Figure 4 – Arrhenius plot when multiple mechanisms are contributing	13
Figure 5 – Structure of ladder filter	14
Figure 6 – Typical transmission characteristic of ladder filter	14
Figure 7 – Creation of voids and hillocks.....	15
Figure 8 – Translation of the filter pass band with temperature change	17
Figure 9 – Basic setup for TF measurement at RF power application	18
Figure 10 – Basic setup for TF measurement of SAW/BAW duplexer	18
Figure 11 – Setup for TF measurement including filter response monitoring.....	19
Figure 12 – Another setup for TF measurement including filter response monitoring	19

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**GUIDELINES FOR THE MEASUREMENT METHOD OF
POWER DURABILITY FOR SURFACE ACOUSTIC WAVE (SAW)
AND BULK ACOUSTIC WAVE (BAW) DEVICES IN
RADIO FREQUENCY (RF) APPLICATIONS**

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FDIS	Report on voting
49/1339/FDIS	49/1342/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

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INTRODUCTION

Radio frequency (RF) surface acoustic wave (SAW) and bulk acoustic wave (BAW) devices are now widely used in various communication systems owing to their features such as small size, light weight, little or no need for tuning, high stability and high reliability.

One of the most important applications of the devices is the antenna duplexer in mobile communication devices which separates incoming receiving (Rx) signals from base-stations and outgoing transmitting (Tx) signals in the frequency domain. It is known that acoustic vibration can accelerate destruction of electrode metals in the inter-digital transducers (IDTs) employed, which results in device failure. Thus, the device life time (time to failure, TF) is dependent on not only the chip temperature but also on input power level and frequency of the applied radio frequency signal. It should be noted that chip temperature can be somewhat different from the environmental temperature because the input power level of Tx signal in the above-mentioned applications is about 1 W at maximum, and heat generation due to power consumption is not negligible.

The requisite TF of the SAW/BAW duplexers is usually specified by input power level, exposure frequency range and environmental temperature. Nevertheless, TF measurement under given specifications is not realistic because the requisite TF is too long (could be up to many years). Accelerated life time testing is applied to shorten the TF. TF is measured in more severe situations, namely at higher power and/or higher ambient temperature. TF under given specifications is estimated by extrapolation based on the Arrhenius model including the inverse power law. Although the model explains the variation of the TF with respect to input power level and temperature well, the parameters appearing in the model need to be determined experimentally, and its procedures have not been well established. Therefore, measurement methods will be specifically established for TF estimation of RF SAW/BAW devices.

This document has been compiled in response to a generally expressed desire on the part of both users and manufacturers for general information on testing condition guidance of RF SAW/BAW filters, so that the filters may be used to their best advantage. To this end, general and fundamental characteristics have been explained in this document.

GUIDELINES FOR THE MEASUREMENT METHOD OF POWER DURABILITY FOR SURFACE ACOUSTIC WAVE (SAW) AND BULK ACOUSTIC WAVE (BAW) DEVICES IN RADIO FREQUENCY (RF) APPLICATIONS

1 Scope

This document defines the measurement method for the determination of the durability of radio frequency (RF) surface acoustic wave (SAW) and bulk acoustic wave (BAW) devices, such as filters and duplexers, with respect to high power RF signals, which are used in telecommunications, measuring equipment, radar systems and consumer products. RF BAW devices include two types: those based on the film bulk acoustic resonator (FBAR) technology and those based on the solidly mounted resonator (SMR) technology.

This document includes basic properties of failure of RF SAW/BAW devices, and guidelines to set up the measurement system and to establish the procedure to estimate the time to failure (TF). Since TF is mainly governed by the RF power applied in the devices, discussions are focused on the power durability.

It is not the aim of this document to explain the theory, nor to attempt to cover all the eventualities which can arise in practical circumstances. This document draws attention to some of the more fundamental questions which will need to be considered by the user before he/she places an order for an RF SAW/BAW device for a new application. Such a procedure will be the user's means of preventing unsatisfactory performance related to premature device failure resulting from high-power exposure of RF SAW/BAW devices.

2 Normative references

There are no normative references in this document.

3 Terms and definitions

3.1 General terms

3.1.1

BAW

bulk acoustic wave

acoustic wave propagating between the top and bottom surface of a piezoelectric structure and then traversing the entire thickness of the piezoelectric bulk

Note 1 to entry: The wave is excited by metal electrodes attached to both sides of the piezoelectric layer.

[SOURCE: IEC 62575-1:2015, 3.1.1]

3.1.2

BAW filter

bulk acoustic wave filter

filter characterised by a bulk acoustic wave which is usually generated by a pair of electrodes and propagates along a thin film thickness direction

[SOURCE: IEC 62575-1:2015, 3.1.2]